DEPARTMENT OF Electronics and Communication Engineering NATIONAL INSTITUTE OF TECHNOLOGY, TIRUCHIRAPPALLI

NATIONAL IN	STITU	TE OF TECHN	OLO	SY, TIRUCH	IIRAPPALLI
		COURSE	PLAN	- PART I	
Name of the programme and specialization	B.Tec	ch (ECE)			
Course Title	VLSI	SYSTEMS			
Course Code	ECPC	226	No.	of Credits	03
Course Code of Pre- requisite subject(s)	Nil				
Session	Jan 2	019	Sect	ion pplicable)	Both A & B
Name of Faculty	Dr. B Venkataramani		-	artment	ECE
Email	-	<u>ki@nitt.edu</u> kii@gmail.com	Tele	phone No.	7708977953 0431 2503303
Name of Course Coordinator(s) (if, applicable)	Nil				
E-mail	NA		Tele	phone No.	NA
Course Type		Core course		Elective co	urse
rules. Stick diagram. La Characteristics of MOS technology, multiplexers	gy, VLS tch up. S and on s and n	CMOS switches. nemory, MOS tran analysis. CMOS	Implen	nentation of l	MOS circuit fabrication. Layout designogic circuits using MOS and CMO oltage, MOS device design equations on delay of inverters, Pseudo NMOS

Programmable logic devices- antifuse, EPROM and SRAM techniques. Programmable logic cells Programmable inversion and expander logic. Computation of interconnect delay, Techniques for drivin large off-chip capacitors, long lines, Computation of interconnect delays in FPGAs Implementation of PLI EPROM, EEPROM, static and dynamic RAM in CMOS.

An overview of the features of advanced FPGAs, IP cores, Softcore processors, Various factor determining the cost of a VLSI, Comparison of ASICs, FPGAs, PDSPs and CBICs. Fault tolerant VLS architectures

VLSI testing -need for testing, manufacturing test principles, design strategies for test, chip level an system level test techniques.

Text Books

- 1. N. H. E. Weste, D.F. Harris, "CMOS VLSI design", (4/e), Pearson, 2015.
- 2. J. Smith, "Application Specific Integrated Circuits, Pearson", 2011.
- 3. M.M. Vai, "VLSI design", CRC Press, 2001.

Reference Books

1. I dekileli & Eshlagilari, Dasic VESI Designi, Fili, (5/6), 200	1.	Pucknell & Eshraghian	n, "Basic VLSI Design", PHI, (3/e), 20	03.
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2. Uyemura, "Introduction to VLSI Circuits and Systems", Wiley, 2002

COURSE OBJECTIVES

To introduce various aspects of VLSI circuits and their design including testing.

COURSE OUTCOMES (CO)

Course Outcomes	Aligned Programme Outcomes (PO)	
1. Describe the techniques used for VLSI fabrication, design of CMOS logic circuits, switches and memory	PO1, PO3, PO4, PO5	
2. Describe the techniques used the design of CMOS logic circuits, switches and memory in VLSI	PO1, PO3, PO4, PO5	
3. Generalize the design techniques and analyze the characteristics of VLSI circuits such as area, speed and power dissipation	PO1, PO2, PO3, PO4, PO5,PO7, PO12	
4. Explain and compare the architectures for FPGA, PAL and PLDs and evaluate their characteristics such as area, power dissipation and reliability	PO1, PO2, PO3, PO4, PO5,PO7, PO12	
5. Describe the techniques for fault tolerant VLSI circuits, Explain and compare the techniques for chip level and board level testing	PO1, PO2, PO3, PO4, PO5,PO7, PO12	

Week	Topic	Mode of Delivery	
Week 1 (3 Contact Hours)	VLSI design methodology, VLSI technology- NMOS, CMOS and BICMOS circuit fabrication.	Lecture C&T/ PPT or any suitable mode	
Week 2 (3 Contact Hours)	Layout design rules. Stick diagram. Latch up. Characteristics of MOS and CMOS switches.		
Week 3 (3 Contact Hours)	Implementation of logic circuits using MOS and CMOS technology, multiplexers and memory,		
Week 4 (3 Contact Hours)	MOS transistors, threshold voltage, MOS device design equations. MOS models, small-signal AC analysis.	Process of the Control of the Contro	
ASSE	SSMENT I - 10 Marks	Quiz	

Week 5 (3 Contact Hours)	CMOS inverters, propagation delay of inverters, Pseudo NMOS, Dynamic CMOS logic circuits, power dissipation.	
Week 6	ASSESSMENT II - 20 Mark	Descriptive/Numerical (Written)
Week 7 (3 Contact Hours)	Programmable logic devices- antifuse, EPROM and SRAM techniques. Programmable logic Cells.	
Week 8 (3 Contact Hours)	Programmable inversion and expander logic. Computation of interconnect delay, Techniques for driving large off-chip capacitors, long lines,	Lecture C&T/ PPT or any suitable mode
Week 9 (3 Contact Hours)	Computation of interconnect delays in FPGAs Implementation of PLD,	
ASSE	SSMENT III - 10 Marks	Quiz
Week 10 (3 Contact Hours)	EPROM, EEPROM, static and dynamic RAM in CMOS.	
Week 11 (3 Contact Hours)	An overview of the features of advanced FPGAs, IP cores, Soft-core processors	Lecture
Week 12	Week 12 Various factors determining the cost of a VLSI, Comparison of	
(3 Contact Hours)		mode
(3 Contact Hours) Week 13	ASICs, FPGAs, PDSPs and CBICs . Fault tolerant VLSI architectures	mode
(3 Contact Hours) Week 13 (3 Contact Hours) Week 14	ASICs, FPGAs, PDSPs and CBICs . Fault tolerant VLSI architectures VLSI testing -need for testing	Descriptive/Numerical

COURS	SE ASSESSMENT METHODS (Week/Date	Duration	% Weightage
S.No.	Mode of Assessment	WeekiDate	60 Minutes	10
5.NO.	Assessment I (Quiz)	1st week Feb	00	
1		3rd Week Feb	60 Minutes	20
0	Assessment II	3.ª WEEKTED		10
2	HI (Ouiz)	2 nd Week of March	60 Minutes	10
3	Assessment III (Quiz)	CNAmala	60 Minutes	20
	Assessment IV	4th Week of March	00 Williams	
4		1st Week of April	60 Minutes	20
	Compensation Assessment*	1St Week of Tapan		
5	Compensation Assessment	4th Week of April	180 Minutes	40
6	Final Assessment *	4 WEER OF TIPM		

*mandatory; refer to guidelines on page 4

COURSE EXIT SURVEY (mention the ways in which the feedback about the course shall be assessed)

Feedback from the students after the lectures are over

COURSE POLICY (preferred mode of correspondence with students, compensation assessment policy to be specified)

MODE OF CORRESPONDENCE (email/ phone etc)

Only email

COMPENSATION ASSESSMENT POLICY

Equal weightage for portions from both Assessment II & IV would be included for the compensation assessment

ATTENDANCE POLICY (A uniform attendance policy as specified below shall be followed)

- At least 75% attendance in each course is mandatory.
- A maximum of 10% shall be allowed under On Duty (OD) category.
- Students with less than 65% of attendance shall be prevented from writing the final assessment and shall be awarded 'V' grade.

ACADEMIC DISHONESTY & PLAGIARISM

- Possessing a mobile phone, carrying bits of paper, talking to other students, copying from others during an assessment will be treated as punishable dishonesty.
- > Zero mark to be awarded for the offenders. For copying from another student, both students get the same penalty of zero mark.
- ➤ The departmental disciplinary committee including the course faculty member, PAC chairperson and the HoD, as members shall verify the facts of the malpractice and award the punishment if the student is found guilty. The report shall be submitted to the Academic office.

The above policy against academic dishonesty shall be applicable for all the programmes.

ADDITIONAL INFORMATION

Every student is expected to score a minimum of Peak/3 or class average/2 whichever is lower of the maximum mark of the class in the total assessment to pass the course. Otherwise the student would be declared fail and 'F' grade will be awarded.

FOR APPROVAL

Course Faculty

CC-Chairperson

Guidelines:

- a) The number of assessments for a course shall range from 4 to 6.
- b) Every course shall have a final assessment on the entire syllabus with at least 30% weightage.
- c) One compensation assessment for absentees in assessments (other than final assessment) is mandatory. Only genuine cases of absence shall be considered.
- d) The passing minimum shall be as per the regulations.

B.Tech. Admitted in				
2018	2017	2016	2015	
35% or class average/2 whichever is greater.		Peak/3 or class whichever is lowe		40%

- e) Attendance policy and the policy on academic dishonesty & plagiarism by students are uniform for all the courses.
- f) Absolute grading policy shall be incorporated if the number of students per course is less than 10.
- g) Necessary care shall be taken to ensure that the course plan is reasonable and is objective.